

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/711,709 | Applicant(s)/Patent Under Reexamination VERSIC ET AL. | |
| | Examiner Kimberly D. Nguyen | Art Unit 2876 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-6,160,526 | 12-2000 | Hirai et al. | 343/895 |
| * | B | US-6,951,596 | 10-2005 | Green et al. | 156/264 |
| * | C | US-5,059,471 | 10-1991 | McNally et al. | 428/143 |
| * | D | US-6,940,408 | 09-2005 | Ferguson et al. | 340/572.7 |
| * | E | US-6,518,887 | 02-2003 | Suzuki et al. | 340/572.8 |
| * | F | US-6,951,596 | 10-2005 | Green et al. | 156/264 |
| * | G | US-7,102,520 | 09-2006 | Liu et al. | 340/572.1 |
| * | H | US-6,607,135 | 08-2003 | Hirai et al. | 235/487 |
| * | I | US-7,061,083 | 06-2006 | Usami et al. | 257/679 |
| * | J | US-2004/0159709 | 08-2004 | Ohta et al. | 235/492 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Yoshihara et al (DE 19957111 A1), Semiconductor component, e.g. wafer of sensor..., 31 May 2000. |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.